Search I	Notes
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Application/Control No.	Applicant(s)/Patent under Reexamination
10/015,848	PAYNE ET AL.
Examiner	Art Unit
Jason M. Perilla	2638

SEARCHED			
Class	Subclass	Date	Examiner
375	346	8/25/2005	JP
	350	8/25/2005	JP
		ű.	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH I (INCLUDING SEAR		')
	DATE	EXMR
East EPO/JPO USPAT/USPGPUB	8/25/2005	JP
Inventor Name Search East/EDAN	8/25/2005	JP
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